

Product data sheet

1. Product profile

1.1 General description

NPN silicon RF transistor for high speed, low noise applications in a plastic, 3-pin SOT323 package.

The BFU530W is part of the BFU5 family of transistors, suitable for small signal to medium power applications up to 2 GHz.

1.2 Features and benefits

- Low noise, high breakdown RF transistor
- AEC-Q101 qualified
- Minimum noise figure (NF_{min}) = 0.6 dB at 900 MHz
- Maximum stable gain 18.5 dB at 900 MHz
- 11 GHz f_T silicon technology

1.3 Applications

- Applications requiring high supply voltages and high breakdown voltages
- Broadband amplifiers up to 2 GHz
- Low noise amplifiers for ISM applications
- ISM band oscillators

1.4 Quick reference data

 Table 1.
 Quick reference data

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{CB}	collector-base voltage	open emitter		-	-	24	V
V _{CE}	collector-emitter voltage	open base		-	-	12	V
		shorted base		-	-	24	V
V_{EB}	emitter-base voltage	open collector		-	-	2	V
I _C	collector current			-	10	40	mΑ
P _{tot}	total power dissipation	T _{sp} ≤ 87 °C	<u>[1]</u>	-	-	450	mW
h _{FE}	DC current gain	$I_C = 10 \text{ mA}; V_{CE} = 8 \text{ V}$		60	95	200	
C _c	collector capacitance	$V_{CB} = 8 \text{ V}; f = 1 \text{ MHz}$		-	0.68	-	pF
f _T	transition frequency	$I_C = 15 \text{ mA}$; $V_{CE} = 8 \text{ V}$; $f = 900 \text{ MHz}$		-	11	-	GHz



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Table 1. Quick reference data ...continued

 $T_{amb} = 25$ °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$G_{p(max)}$	maximum power gain	$I_C = 10 \text{ mA}; V_{CE} = 8 \text{ V}; f = 900 \text{ MHz}$	[2] _	18.5	-	dB
NF _{min}	minimum noise figure	I_C = 1 mA; V_{CE} = 8 V; f = 900 MHz; Γ_S = Γ_{opt}	-	0.6	-	dB
P _{L(1dB)}	output power at 1 dB gain compression	I_{C} = 15 mA; V_{CE} = 8 V; Z_{S} = Z_{L} = 50 Ω ; f = 900 MHz	-	10	-	dBm

- [1] T_{sp} is the temperature at the solder point of the collector lead.
- [2] If K > 1 then $G_{p(max)}$ is the maximum power gain. If K < 1 then $G_{p(max)} = MSG$.

2. Pinning information

Table 2. Discrete pinning

	2.00.0to p		
Pin	Description	Simplified outline	Graphic symbol
1	base		2
2	emitter	3	<u>3</u>
3	collector		1—
		1 - 2	2
			aaa-010458

3. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BFU530W	-	plastic surface-mounted package; 3 leads	SOT323			
OM7960	-	Customer evaluation kit for BFU520W, BFU530W and BFU550W [1]	-			

- [1] The customer evaluation kit contains the following:
 - a) Unpopulated RF amplifier Printed-Circuit Board (PCB)
 - b) Unpopulated RF amplifier Printed-Circuit Board (PCB) with emitter degeneration
 - c) Four SMA connectors for fitting unpopulated Printed-Circuit Board (PCB)
 - d) BFU520W, BFU530W and BFU550W samples
 - e) USB stick with data sheets, application notes, models, S-parameter and noise files

4. Marking

Table 4. Marking

Type number	Marking	Description		
BFU530W	ZB*	* = t : made in Malaysia		
		* = w : made in China		

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5. Design support

Table 5. Available design support

Download from the BFU530W product information page on http://www.nxp.com.

Support item	Available	Remarks
Device models for Agilent EEsof EDA ADS	yes	Based on Mextram device model.
SPICE model	yes	Based on Gummel-Poon device model.
S-parameters	yes	
Noise parameters	yes	
Customer evaluation kit	yes	See Section 3 and Section 10.
Solder pattern	yes	
Application notes	yes	See Section 10.1 and Section 10.2.

6. Limiting values

Table 6. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CB}	collector-base voltage	open emitter	-	30	V
V_{CE}	collector-emitter voltage	open base	-	16	V
		shorted base	-	30	V
V_{EB}	emitter-base voltage	open collector	-	3	V
I _C	collector current		-	65	mΑ
T _{stg}	storage temperature		-65	+150	°C
V_{ESD}	electrostatic discharge voltage	Human Body Model (HBM) According to JEDEC standard 22-A114E	-	±150	V
		Charged Device Model (CDM) According to JEDEC standard 22-C101B	-	±2	kV

7. Recommended operating conditions

Table 7. Characteristics

Parameter	Conditions	Min	Тур	Max	Unit
collector-base voltage	open emitter	-	-	24	V
collector-emitter voltage	open base	-	-	12	V
	shorted base	-	-	24	V
emitter-base voltage	open collector	-	-	2	V
collector current		-	-	40	mA
input power	$Z_S = 50 \Omega$	-	-	10	dBm
junction temperature		-40	-	+150	°C
total power dissipation	T _{sp} ≤ 87 °C	[1] _	-	450	mW
	collector-base voltage collector-emitter voltage emitter-base voltage collector current input power junction temperature	$ \begin{array}{c} \text{collector-base voltage} & \text{open emitter} \\ \text{collector-emitter voltage} & \text{open base} \\ \text{shorted base} \\ \text{emitter-base voltage} & \text{open collector} \\ \text{collector current} \\ \text{input power} & Z_S = 50~\Omega \\ \text{junction temperature} \\ \end{array} $	$\begin{array}{c} \text{collector-base voltage} & \text{open emitter} & - \\ \text{collector-emitter voltage} & \text{open base} & - \\ \text{shorted base} & - \\ \text{emitter-base voltage} & \text{open collector} & - \\ \text{collector current} & - \\ \text{input power} & Z_S = 50~\Omega & - \\ \text{junction temperature} & -40 \\ \end{array}$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

^[1] T_{sp} is the temperature at the solder point of the collector lead.

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8. Thermal characteristics

Table 8. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point		[<u>1]</u> 140	K/W

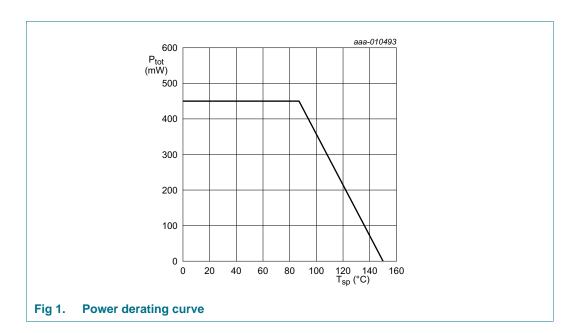
[1] T_{sp} is the temperature at the solder point of the collector lead.

 T_{sp} has the following relation to the ambient temperature T_{amb} :

 $T_{sp} = T_{amb} + P \times R_{th(sp-a)}$

With P being the power dissipation and $R_{th(sp-a)}$ being the thermal resistance between the solder point and ambient. $R_{th(sp-a)}$ is determined by the heat transfer properties in the application.

The heat transfer properties are set by the application board materials, the board layout and the environment e.g. housing.



9. Characteristics

Table 9. Characteristics

T_{amb} = 25 °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)CBO}$	collector-base breakdown voltage	$I_C = 100 \text{ nA}; I_E = 0 \text{ mA}$	24	-	-	V
$V_{(BR)CEO}$	collector-emitter breakdown voltage	$I_C = 150 \text{ nA}; I_B = 0 \text{ mA}$	12	-	-	V
I_{C}	collector current		-	10	40	mΑ
I_{CBO}	collector-base cut-off current	$I_E = 0 \text{ mA}; V_{CB} = 8 \text{ V}$	-	<1	-	nΑ
h _{FE}	DC current gain	$I_C = 10 \text{ mA}; V_{CE} = 8 \text{ V}$	60	95	200	
C _e	emitter capacitance	$V_{EB} = 0.5 V; f = 1 MHz$	-	0.84	-	pF
C_{re}	feedback capacitance	$V_{CE} = 8 \text{ V}; f = 1 \text{ MHz}$	-	0.43	-	pF
C _c	collector capacitance	$V_{CB} = 8 \text{ V}; f = 1 \text{ MHz}$	-	0.68	-	pF
f_{T}	transition frequency	$I_C = 15 \text{ mA}$; $V_{CE} = 8 \text{ V}$; $f = 900 \text{ MHz}$	-	11	-	GHz

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Table 9. Characteristics ... continued $T_{amb} = 25$ °C unless otherwise specified

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$G_{p(max)}$	maximum power gain	$f = 433 \text{ MHz}; V_{CE} = 8 \text{ V}$	<u>[1]</u>				
		I _C = 1 mA		-	15.5	-	dB
		I _C = 10 mA		-	23.5	-	dB
		I _C = 15 mA		-	24	-	dB
		f = 900 MHz; V _{CE} = 8 V	<u>[1]</u>				
		I _C = 1 mA		-	12.5	-	dB
		I _C = 10 mA		-	18.5	-	dB
		I _C = 15 mA		-	19	-	dB
		f = 1800 MHz; V _{CE} = 8 V	[1]				
		I _C = 1 mA		-	10.5	-	dB
		I _C = 10 mA		-	12.5	-	dB
		I _C = 15 mA		-	12.5	-	dB
$ s_{21} ^2$	insertion power gain	$f = 433 \text{ MHz}; V_{CE} = 8 \text{ V}$					
		I _C = 1 mA		-	10	-	dB
		I _C = 10 mA		-	21.5	-	dB
		I _C = 15 mA		-	22	-	dB
		f = 900 MHz; V _{CE} = 8 V					
		I _C = 1 mA		-	8.5	-	dB
		I _C = 10 mA		-	16	-	dB
		I _C = 15 mA		-	16	-	dB
		f = 1800 MHz; V _{CE} = 8 V					
		I _C = 1 mA		-	5	-	dB
		I _C = 10 mA		-	10.5	-	dB
		I _C = 15 mA		-	10.5	-	dB
NF _{min}	minimum noise figure	f = 433 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}					
		I _C = 1 mA		-	0.5	-	dB
		I _C = 10 mA		-	8.0	-	dB
		I _C = 15 mA		-	0.9	-	dB
		f = 900 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}					
		I _C = 1 mA		-	0.6	-	dB
		I _C = 10 mA		-	0.9	-	dB
		I _C = 15 mA		-	1.0	-	dB
		f = 1800 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}					
		I _C = 1 mA		-	8.0	-	dB
		I _C = 10 mA		-	1.0	-	dB
		I _C = 15 mA			1.1		dB

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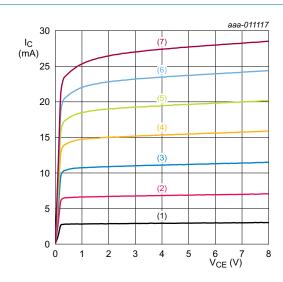
Table 9. Characteristics ... continued $T_{amb} = 25$ °C unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G _{ass}	associated gain	f = 433 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	22.5	-	dB
		I _C = 10 mA	-	22.5	-	dB
		I _C = 15 mA	-	23	-	dB
		f = 900 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	14.5	-	dB
		I _C = 10 mA	-	16.5	-	dB
		I _C = 15 mA	-	17	-	dB
		f = 1800 MHz; V_{CE} = 8 V; Γ_{S} = Γ_{opt}				
		I _C = 1 mA	-	8.5	-	dB
		I _C = 10 mA	-	11	-	dB
		I _C = 15 mA	-	11	-	dB
L(1dB)	output power at 1 dB gain compression	f = 433 MHz; V_{CE} = 8 V; Z_{S} = Z_{L} = 50 Ω				
		I _C = 10 mA	-	6	-	dBm
		I _C = 15 mA	-	9.5	-	dBm
		f = 900 MHz; V_{CE} = 8 V; Z_{S} = Z_{L} = 50 Ω				
		I _C = 10 mA	-	7	-	dBm
		I _C = 15 mA	-	10	-	dBm
		f = 1800 MHz; V_{CE} = 8 V; Z_{S} = Z_{L} = 50 Ω				
		I _C = 10 mA	-	8	-	dBm
		I _C = 15 mA	-	10.5	-	dBm
P3 _o	output third-order intercept point	f_1 = 433 MHz; f_2 = 434 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 10 mA	-	16	-	dBm
		I _C = 15 mA	-	19	-	dBm
		f_1 = 900 MHz; f_2 = 901 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 10 mA	-	17	-	dBm
		I _C = 15 mA	-	20	-	dBm
		f_1 = 1800 MHz; f_2 = 1801 MHz; V_{CE} = 8 V; Z_S = Z_L = 50 Ω				
		I _C = 10 mA	-	18	-	dBm
		I _C = 15 mA	-	20	-	dBm

^[1] If K > 1 then $G_{p(max)}$ is the maximum power gain. If K < 1 then $G_{p(max)} = MSG$.

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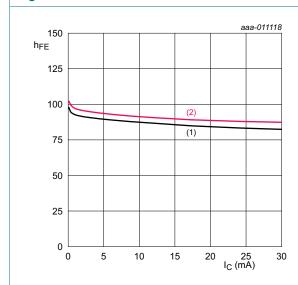
9.1 Graphs



 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $I_B = 25 \mu A$
- (2) $I_B = 75 \mu A$
- (3) $I_B = 125 \mu A$
- (4) $I_B = 175 \mu A$
- (5) $I_B = 225 \mu A$
- (6) $I_B = 275 \mu A$
- (7) $I_B = 325 \mu A$

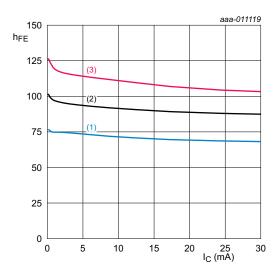
Fig 2. Collector current as a function of collector-emitter voltage; typical values



 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

Fig 3. DC current gain as function of collector current; typical values



 $V_{CE} = 8 V.$

- (1) $T_{amb} = -40 \, ^{\circ}C$
- (2) $T_{amb} = +25 \, ^{\circ}C$
- (3) $T_{amb} = +125 \, ^{\circ}C$

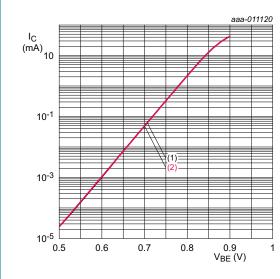
Fig 4. DC current gain as function of collector current; typical values

BFU530W

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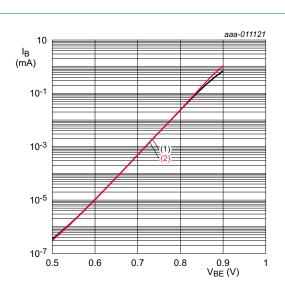
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 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

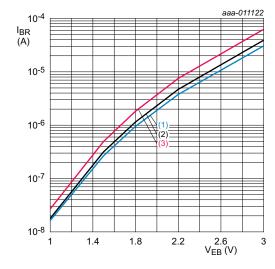
Fig 5. Collector current as a function of base-emitter voltage; typical values



 $T_{amb} = 25 \, ^{\circ}C$.

- (1) $V_{CE} = 3.0 \text{ V}$
- (2) $V_{CE} = 8.0 \text{ V}$

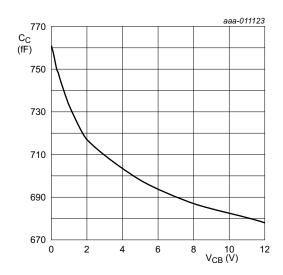
Fig 6. Base current as a function of base-emitter voltage; typical values



V_{CE} = 3 V.

- (1) $T_{amb} = -40 \, ^{\circ}C$
- (2) $T_{amb} = +25 \, ^{\circ}C$
- (3) $T_{amb} = +125 \, ^{\circ}C$

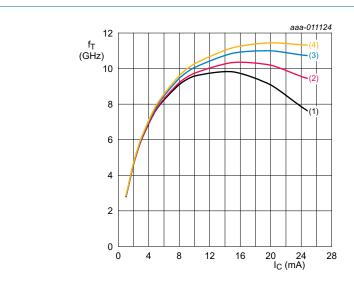
Fig 7. Reverse base current as a function of emitter-base voltage; typical values



 $I_C = 0$ mA; f = 1 MHz; $T_{amb} = 25$ °C.

Fig 8. Collector capacitance as a function of collector-base voltage; typical values

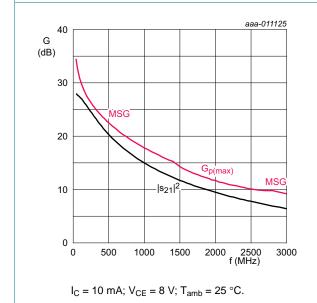
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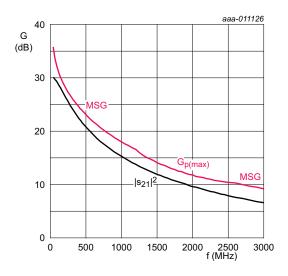
 $T_{amb} = 25 \, ^{\circ}C.$

- (1) $V_{CE} = 3.3 \text{ V}$
- (2) $V_{CE} = 5.0 \text{ V}$
- (3) $V_{CE} = 8.0 \text{ V}$
- (4) $V_{CE} = 12.0 \text{ V}$

Fig 9. Transition frequency as a function of collector current; typical values



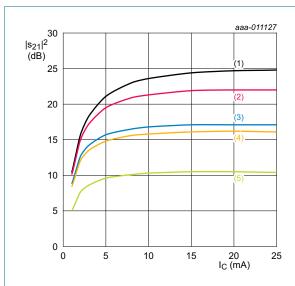




 I_C = 15 mA; V_{CE} = 8 V; T_{amb} = 25 °C.

Fig 11. Gain as a function of frequency; typical values

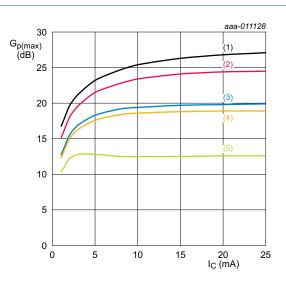
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 V_{CE} = 8 V; T_{amb} = 25 °C.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz





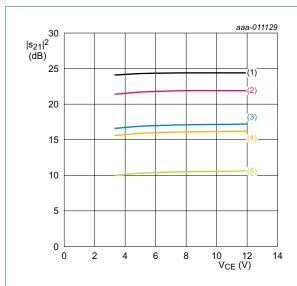
 V_{CE} = 8 V; T_{amb} = 25 °C.

If K >1 then $G_{p(max)}$ = maximum power gain. If K < 1 then $G_{p(max)}$ = MSG.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz

Fig 13. Maximum power gain as a function of collector current; typical values

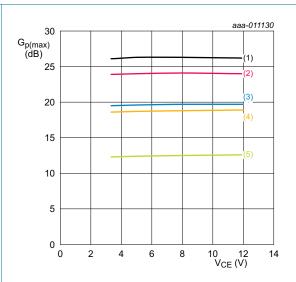
NPN wideband silicon RF transistor



 I_C = 15 mA; T_{amb} = 25 °C.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz





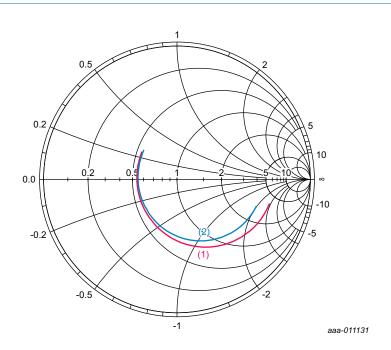
 I_C = 15 mA; T_{amb} = 25 °C.

If K >1 then $G_{p(max)}$ = maximum power gain. If K < 1 then $G_{p(max)}$ = MSG.

- (1) f = 300 MHz
- (2) f = 433 MHz
- (3) f = 800 MHz
- (4) f = 900 MHz
- (5) f = 1800 MHz

Fig 15. Maximum power gain as a function of collector-emitter voltage; typical values

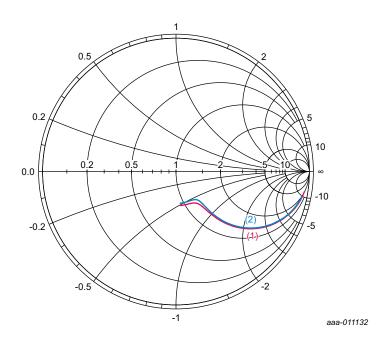
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 V_{CE} = 8 V; 40 MHz \leq f \leq 3 GHz.

- (1) $I_C = 10 \text{ mA}$
- (2) $I_C = 15 \text{ mA}$

Fig 16. Input reflection coefficient (s₁₁); typical values



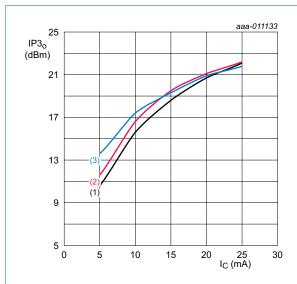
 V_{CE} = 8 V; 40 MHz \leq f \leq 3 GHz.

- (1) $I_C = 10 \text{ mA}$
- (2) $I_C = 15 \text{ mA}$

Fig 17. Output reflection coefficient (s_{22}) ; typical values

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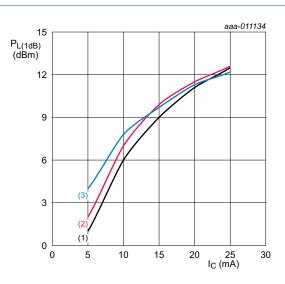
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 $V_{CE} = 8 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}.$

- (1) $f_1 = 433 \text{ MHz}$; $f_2 = 434 \text{ MHz}$
- (2) $f_1 = 900 \text{ MHz}$; $f_2 = 901 \text{ MHz}$
- (3) $f_1 = 1800 \text{ MHz}$; $f_2 = 1801 \text{ MHz}$

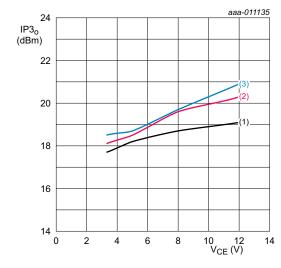
Fig 18. Output third-order intercept point as a function of collector current; typical values



 $V_{CE} = 8 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}.$

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

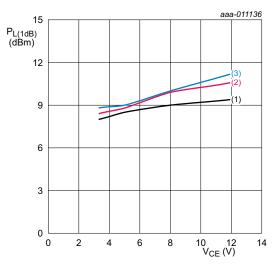
Fig 19. Output power at 1 dB gain compression as a function of collector current; typical values



 I_C = 10 mA; T_{amb} = 25 °C.

- (1) $f_1 = 433 \text{ MHz}$; $f_2 = 434 \text{ MHz}$
- (2) $f_1 = 900 \text{ MHz}$; $f_2 = 901 \text{ MHz}$
- (3) $f_1 = 1800 \text{ MHz}$; $f_2 = 1801 \text{ MHz}$

Fig 20. Output third-order intercept point as a function of collector-emitter voltage; typical values

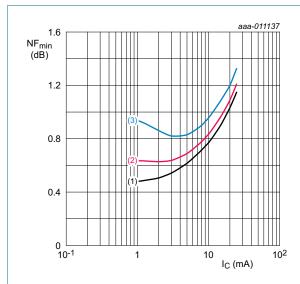


 $I_C = 10 \text{ mA}$; $T_{amb} = 25 \,^{\circ}\text{C}$.

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

Fig 21. Output power at 1 dB gain compression as a function of collector-emitter voltage; typical values

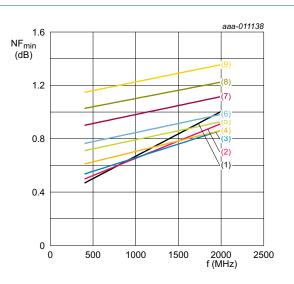
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$$V_{CE}$$
 = 8 V; T_{amb} = 25 °C; Γ_{S} = Γ_{opt} .

- (1) f = 433 MHz
- (2) f = 900 MHz
- (3) f = 1800 MHz

Fig 22. Minimum noise figure as a function of collector current; typical values

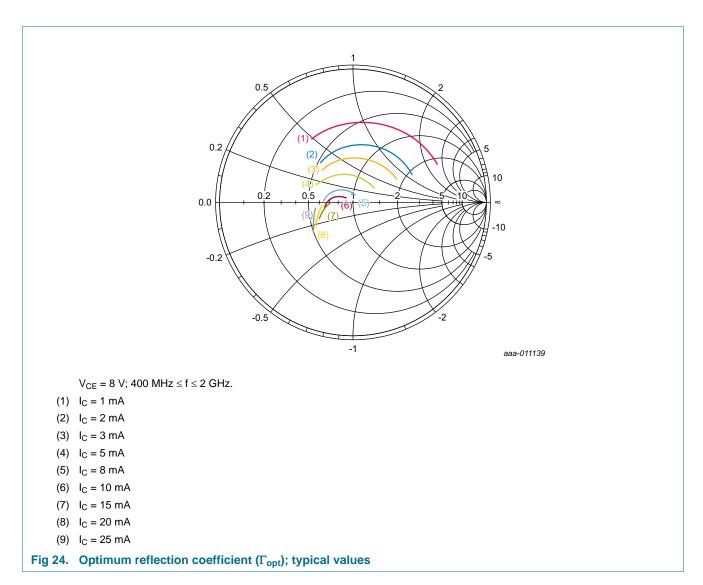


$$V_{CE} = 8 \text{ V}; T_{amb} = 25 \text{ °C}; \Gamma_{S} = \Gamma_{opt}.$$

- (1) $I_C = 1 \text{ mA}$
- (2) $I_C = 2 \text{ mA}$
- (3) $I_C = 3 \text{ mA}$
- (4) $I_C = 5 \text{ mA}$
- (5) $I_C = 8 \text{ mA}$
- (6) $I_C = 10 \text{ mA}$ (7) $I_C = 15 \text{ mA}$
- (8) $I_C = 20 \text{ mA}$
- (9) $I_C = 25 \text{ mA}$

Fig 23. Minimum noise figure as a function of frequency; typical values

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10. Application information

More information about the following application example can be found in the application notes. See Section 5 "Design support".

The following application example can be implemented using the evaluation kit. See <u>Section 3 "Ordering information"</u> for the order type number.

The following application example can be simulated using the simulation package. See Section 5 "Design support".

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10.1 Application example: 433 ISM band LNA

433 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11423*.

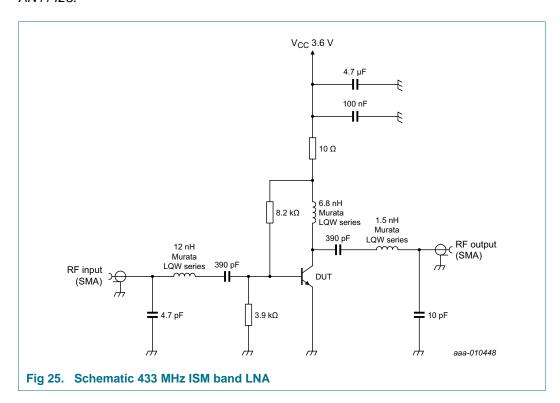


Table 10. Application performance data at 433 MHz $I_{CC} = 10 \text{ mA}$; $V_{CC} = 3.6 \text{ V}$

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ s_{21} ^2$	insertion power gain		-	17	-	dB
NF	noise figure		-	1.1	-	dB
IP3 _o	output third-order intercept point	$f_1 = 433.1 \text{ MHz}; f_2 = 433.2 \text{ MHz};$ $P_i = -30 \text{ dBm per carrier}$	-	9	-	dBm

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10.2 Application example: 866 ISM band LNA

866 ISM band LNA, optimized for low noise.

More detailed information of the application example can be found in the application note: *AN11424*.

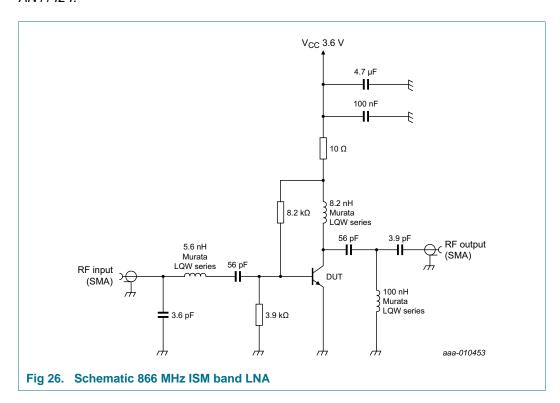


Table 11. Application performance data at 866 MHz

 $I_{CC} = 10 \text{ mA}; V_{CC} = 3.6 \text{ V}$

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ s_{21} ^2$	insertion power gain		-	15	-	dB
NF	noise figure		-	1.1	-	dB
IP3 _o	output third-order intercept point	$f_1 = 866.1 \text{ MHz}; f_2 = 866.2 \text{ MHz};$ $P_i = -30 \text{ dBm per carrier}$	-	17	-	dBm

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11. Package outline

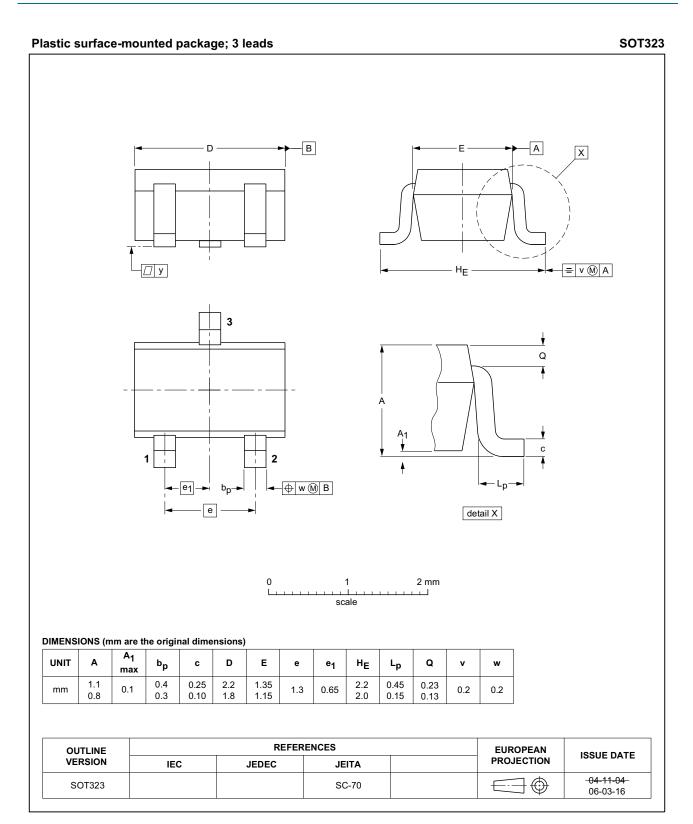


Fig 27. Package outline SOT323

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12. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

13. Abbreviations

Table 12. Abbreviations

Acronym	Description	
AEC	Automotive Electronics Council	
ISM	Industrial, Scientific and Medical	
LNA	Low-Noise Amplifier	
MSG	Maximum Stable Gain	
NPN	Negative-Positive-Negative	
SMA	SubMiniature version A	

14. Revision history

Table 13. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BFU530W v.1	20140113	Product data sheet	-	-

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15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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